

(19) World Intellectual Property Organization
International Bureau



(43) International Publication Date
28 September 2006 (28.09.2006)

PCT

(10) International Publication Number
WO 2006/100663 A1

(51) International Patent Classification:

G01J 5/20 (2006.01)

(21) International Application Number:

PCT/IL2006/000048

(22) International Filing Date: 12 January 2006 (12.01.2006)

(25) Filing Language:

English

(26) Publication Language:

English

(30) Priority Data:

167637

24 March 2005 (24.03.2005) IL

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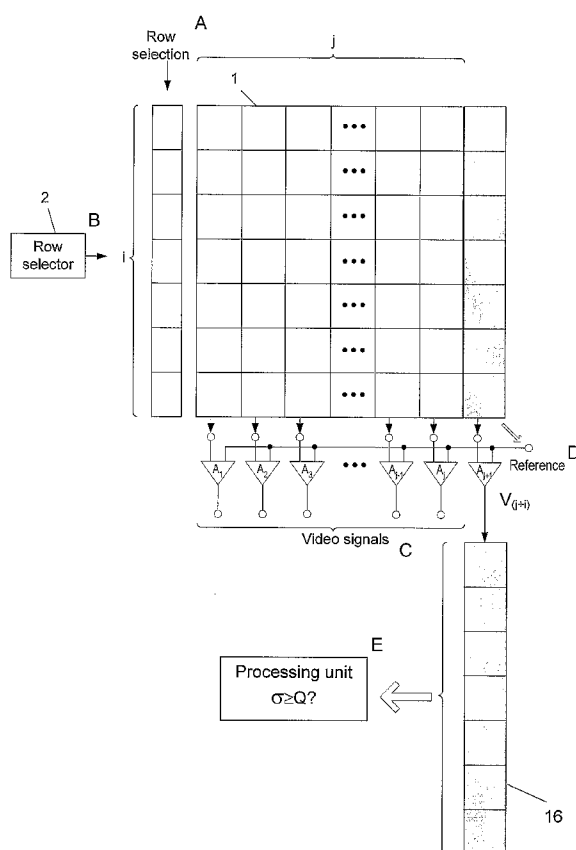
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(81) Designated States (unless otherwise indicated, for every kind of national protection available): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KM, KN, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, LY, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NG, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SM, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

(84) Designated States (unless otherwise indicated, for every kind of regional protection available): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI,

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(54) Title: METHOD AND SYSTEM FOR DETERMINING THE RATE OF NON UNIFORMITY OF BOLOMETER BASED SYSTEMS



(57) Abstract: A focal plan array system of the bolometer type having means for determining the rate of non-uniformity which comprises: (a) an array of $i \times j$ pixel detectors of the bolometer type for sensing scenery radiation; (b) a case which accommodates said array of detectors, said case having a front window that provides exposure to the sensing element of all the $i \times j$ pixel detectors to radiation coming from the scenery; (c) at least a portion of column $j + 1$ of blind detectors that are shielded from the scenery by a homogeneous reference surface; (d) reading circuitry for reading indication for the scenery radiation as sensed by each of the $i \times j$ detectors of the array, and for reading indication for the non uniformity as sensed by said detectors in column $(j+1)$; (e) a register for recording the radiation values as read from all the detectors within column $(j+1)$; and (f) a processing unit for finding the standard deviation σ of all the values in said register, and for comparing the same to a predetermined threshold Q , wherein a standard deviation above Q being an indication for a non uniformity above the allowed level.



FR, GB, GR, HU, IE, IS, IT, LT, LU, LV, MC, NL, PL, PT,
RO, SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA,
GN, GQ, GW, ML, MR, NE, SN, TD, TG).

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